SSM SUSUMU





Electrical Specification

Туре	Power ratings			Temperature coefficient of resistance	Resistance range (Ω) Resistance tolerance $(\%)$				Maximum voltage	Resistance value series	Operating temperature	Pakaging quantity
	Low	Regular	High	(ppm/°C)	±0.02% (P)	±0.05% (W)	±0.1% (B)	±0.5%(D)				
	1/32W	1/16W	1/8W	±5(V)		100≦	R<3k					
RG1005				±10(N)	100≦R<3k 47≦R<100k			75V			T5	
				±25(P)	100≦R<3k	47≦R•	<100k	47≦R<150k	750	E-24,	-55℃	T10
				±100(R)	_	_	—	10≦R<47	1			
RG1608	1/16W	1/1004		±5(V)		100≦F	}<5.1k					
			1/6W	±10(N)	100≦R<5.1k		47≦R≦270k		100V			
		1/1000	1/000	±25(P)	100≦R<5.1k	47≦R≦270k	47≦R≦332k	47≦R≦1M	1000			
				±50(Q)	—	_	—	10≦R<47				
RG2012	1/10W	1/8W	1/4W	±5(V)	100≦R<10.2k					E-96	~ 155℃	
				±10(N)	100≦R<10.2k		47≦R≦475k	150V			Т5	
				±25(P)	100≦R<10.2k	47≦R≦475k	47≦R	≦2.7M	1500			15
				±50(Q)	_	_	—	10≦R<47				
RG3216	1/8W	1/4W	/	±5(V)		100≦R<33.2k						
				±10(N)	100≦R<33.2k		47≦R≦1M		200V			
				±25(P)	100≦R<33.2k	47≦R≦1M	47≦R	≦5.1M				
				±50(Q)	_	_	_	10≦R<47				

Dimensions



Туре	Size (inch)	L	W	а	b	t	
RG1005	0402	1.00+0.1/-0.05	0.50±0.05	0.20±0.10	0.25±0.05	0.35±0.05	
RG1608	0603	1.60±0.20	0.80±0.20	0.30±0.20	0.30±0.20	0.40±0.10	
RG2012	0805	2.00±0.20	1.25±0.20	0.40±0.20	0.40±0.20	0.40±0.10	
RG3216	1206	3.20±0.20	1.60±0.20	0.50±0.25	0.50±0.20	0.40±0.10	
		•				(unit : mm)	

(E-24: 3 digit, E-96: 4 digit, RG3216: all 4 digit)

(unit:mm)

3G series

Thin film surface mount resistors

SSMSUSUMU

Delichility encoification									
Reliability specification			Low		Regular		High		
Test Items	Condition (test methods)	≦47Ω	≧47Ω	≦47Ω	≧47Ω	≦47Ω	≧47Ω	Low	
Short time overload	2.5 x rated voltage, ¹ 5 seconds	±0.10%	±0.05%	±0.10%	±0.05%	_	±0.10%	±(0.01%)	
Life (biased)	70°C, rated voltage,1 90min on 30min off, 1000hours		±0.10%	±0.50%	±0.25%	_	±0.50%	±(0.01%)	
High temperature high humidity	85°C, 85%RH, 1/10 of rated power, 90min on 30min off, 1000hours	±0.25%	±0.10%	±0.50%	±0.25%	_	±0.50%	±(0.05%)	
Temperature shock	-55°C (30min) \sim 125°C (30min) 1000cycles	±0.25%	±0.10%	±0.25%	±0.10%	_	±0.10%	±(0.01%)	
High temperature exposure	155°C, no bias, 1000hours	±0.25%	±0.10%	±0.25%	±0.10%	—	±0.10%	±(0.01%)	
Resistance to soldering heat	260±5°C, 10 seconds (reflow)	±0.1%	±0.1%	±0.1%	±0.1%	-	±0.1%	±(0.01%)	
1 Rated voltage is given by $E = \sqrt{R \times P}$ $E = rated voltage (V), R = nominal resistance value(\Omega), P = rated power(W)$									

1 Rated voltage is given by $E = \sqrt{R \times P}$ E = rated voltage (V), R=nominal resistance value(Ω), P=rated power(W) If rated voltage exceeds maximum voltage /element, maximum voltage/element is the rated voltage.

10000 hour reliability test data

OBiased life test



OTemperature shock



OHigh temperature high humidity (biased)



OHigh temperature exposure



Derating Curve



Maximum pulse power limit



Test procedure

Voltage pulse is applied to the test samples mounted on the test board.

After each pulse, resistance drift is measured. Pulse voltage is increased until the drift exceeds +/-0.5%. The power at that voltage is defined as the maximum pulse power.

RG series